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EIA STANDARD

Reality Block Diagrams

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(IEC 61078:2016, IDT)

January 2018



Electronic Components Industry Association

EIA-61078

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

RELIABILITY BLOCK DIAGRAMS

FOREWORD

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This third edition cancels and replaces the second edition published in 2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the structure of the document has been entirely reconsidered, the title modified and the content extended and improved to provide more information about availability, reliability and failure frequency calculations;
- b) Clause 3 has been extended and clauses have been introduced to describe the electrical analogy, the "non-coherent" RBDs and the "dynamic" RBDs;
- c) Annex B about Boolean algebra methods has been extended;
- d) Annex C (Calculations of time dependent probabilities), Annex D (Importance factors), Annex E (RBD driven Petri net models) and Annex F (Numerical examples and curves) have been introduced.

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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